

Session MM

CAD for Yield and Noise Characterization

Chairman:

Mark C. Calcaterra

USAF

Wright Laboratories

WPAFB, OH

The emergence of MMIC technology has prompted the development of computer based tools for yield optimization, noise analysis, and MMIC packaging. This session emphasizes physics-based CAD and realistic statistical descriptions.



**1:30 p.m.–3:00 p.m., Thursday, June 13, 1991
Ballroom C**